

STL16N65M5

N-channel 650 V, 0.270 Ω, 12 A PowerFLAT™ 8x8 HV MDmesh™ V Power MOSFET

Features

Order code	V _{DSS} @ T _{Jmax}	R _{DS(on)} max	I _D
STL16N65M5	710 V	< 0.299 Ω	12 A ⁽¹⁾

- 1. The value is rated according to $R_{thj-case}$
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

Applications

Switching applications

Description

This device is an N-channel MDmesh[™] V Power MOSFET based on an innovative proprietary vertical process technology, which is combined with STMicroelectronics' well-known PowerMESH[™] horizontal layout structure. The resulting product has extremely low onresistance, which is unmatched among siliconbased Power MOSFETs, making it especially suitable for applications which require superior power density and outstanding efficiency.

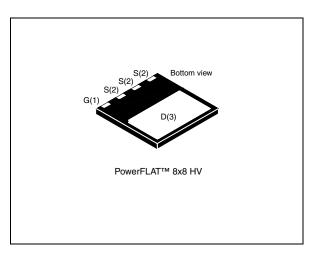


Figure 1. Internal schematic diagram

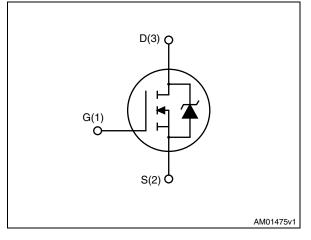


Table 1. Device summary

Order code	Marking	Package	Packaging
STL16N65M5	16N65M5	PowerFLAT™ 8x8 HV	Tape and reel

November 2011

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Absolute maximum ratings

Electrical ratings

Table 2.

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage ($V_{GS} = 0$)	650	V
V _{GS}	Gate-source voltage	± 25	V
I _D ⁽¹⁾	Drain current (continuous) at $T_C = 25 \text{ °C}$	12	А
I _D ⁽¹⁾	Drain current (continuous) at $T_C = 100 \text{ °C}$	7.4	А
I _{DM} ^{(1),(2)}	Drain current (pulsed)	48	А
۱ _D ⁽³⁾	Drain current (continuous) at T _{amb} = 25 °C	2	А
I _D ⁽³⁾	Drain current (continuous) at T _{amb} = 100 °C	1.3	А
I _{DM} ^{(2),(3)}	Drain current (pulsed)	8	А
P _{TOT} ⁽³⁾	Total dissipation at $T_{amb} = 25 \text{ °C}$	3	W
P _{TOT} ⁽¹⁾	Total dissipation at $T_C = 25 \ ^{\circ}C$	90	W
I _{AR}	Avalanche current, repetitive or not- repetitive (pulse width limited by T _j max)	4	A
E _{AS}	Single pulse avalanche energy (starting $T_j = 25 \text{ °C}$, $I_D = I_{AR}$, $V_{DD} = 50 \text{ V}$)	200	mJ
dv/dt (4)	Peak diode recovery voltage slope	15	V/ns
T _{stg}	Storage temperature	- 55 to 150	°C
Тj	Max. operating junction temperature	150	°C

1. The value is rated according to ${\rm R}_{\rm thj\text{-}case}$

2. Pulse width limited by safe operating area

3. When mounted on FR-4 board of inch², 2oz Cu

4. $I_{SD} \leq 12$ A, di/dt ≤ 400 A/µs, V_{Peak} < V_{(BR)DSS}, V_{DD} = 400 V

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case max	1.38	°C/W
R _{thj-amb} ⁽¹⁾	Thermal resistance junction-amb max	45	°C/W

1. When mounted on 1 inch² FR-4 board, 2 oz Cu



Electrical characteristics 2

(T_C = 25 °C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage (V _{GS} = 0)	I _D = 1 mA	650			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = 650 V V _{DS} = 650 V, T _C =125 °C			1 100	μA μA
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 25 V			100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	3	4	5	V
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10 V, I _D = 6 A		0.270	0.299	Ω

Table 4. On /off states

Table 5. Dynamic

	Dynamo					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V_{DS} = 100 V, f = 1 MHz, V_{GS} = 0	-	1250 30 3	-	pF pF pF
C _{o(tr)} ⁽¹⁾	Equivalent capacitance time related	V _{DS} = 0 to 520 V, V _{GS} = 0	-	100	-	pF
C _{o(er)} ⁽²⁾	Equivalent capacitance energy related	$v_{\rm DS} = 0.00320$ v, $v_{\rm GS} = 0.0000$	-	30	-	pF
R _G	Intrinsic gate resistance	f = 1 MHz open drain	-	2	-	Ω
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V_{DD} = 520 V, I_D = 6 A, V_{GS} = 10 V (see <i>Figure 16</i>)	-	31 8 12	-	nC nC nC

C_{oss eq} time related is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}
C_{oss eq} energy related is defined as a constant equivalent capacitance giving the same stored energy as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}



Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
t _d (v)	Voltage delay time	V _{DD} = 400 V, I _D = 8 A,		25		ns
t _r (v)	Voltage rise time	R _G = 4.7 Ω, V _{GS} = 10 V		7		ns
t _f (i)	Current fall time	(see Figure 17),	-	6	-	ns
t _c (off)	Crossing time	(see Figure 20)		8		ns

Table 6.Switching times

Table 7.Source drain diode

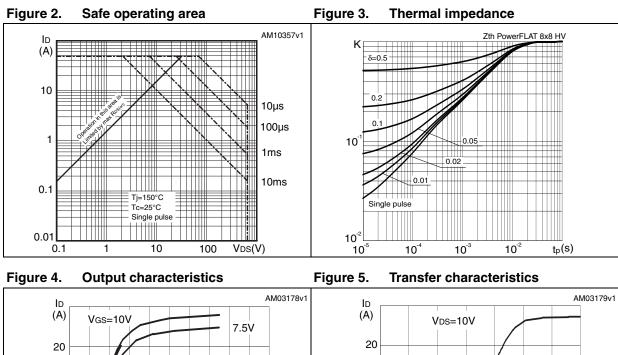
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} ⁽¹⁾	Source-drain current Source-drain current (pulsed)		-		12 48	A A
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 12 A, V _{GS} = 0	-		1.5	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} = 12 A, di/dt = 100 A/μs V _{DD} = 100 V (see <i>Figure 17</i>)	-	300 3.5 23		ns μC Α
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 12 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$ $V_{DD} = 100 \text{ V}, \text{ T}_{\text{j}} = 150 ^{\circ}\text{C}$ (see <i>Figure 17</i>)	-	350 4 24		ns μC Α

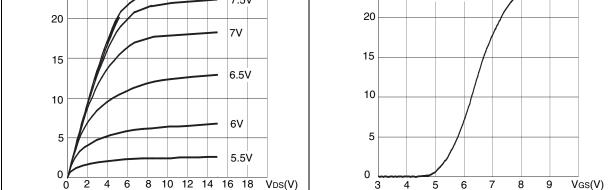
1. Pulse width limited by safe operating area

2. Pulsed: pulse duration = 300 μ s, duty cycle 1.5%

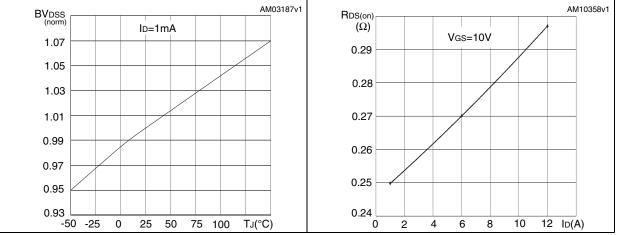


2.1 Electrical characteristics (curves)









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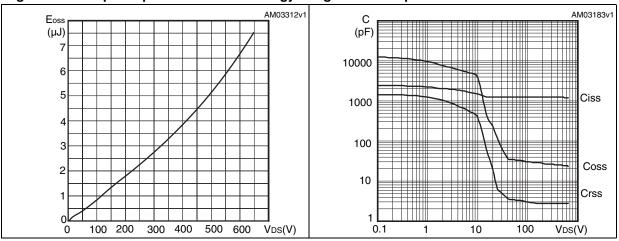


Figure 8. Output capacitance stored energy Figure 9. Capacitance variations

Figure 10. Gate charge vs gate-source voltage Figure 11. Normalized on resistance vs temperature

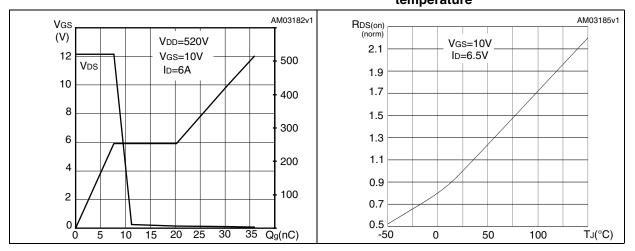
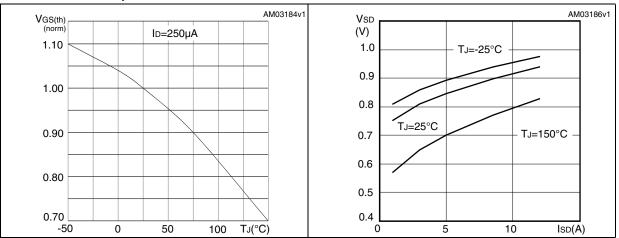


Figure 12. Normalized gate threshold voltage Figure 13. Source vs temperature chara





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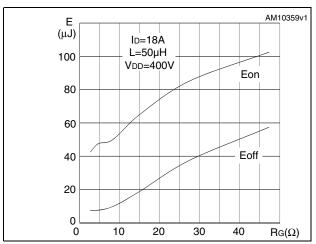


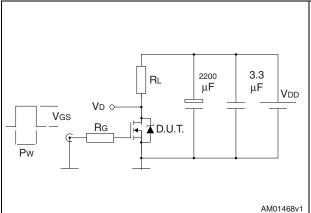
Figure 14. Switching losses vs gate resistance (1)

1. Eon including reverse recovery of a SiC diode



3 Test circuits

Figure 15. Switching times test circuit for resistive load



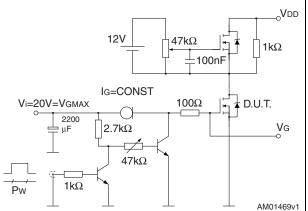
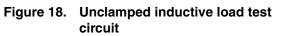


Figure 16. Gate charge test circuit

Figure 17. Test circuit for inductive load switching and diode recovery times



I

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D.U.T.

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μF

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3.3

μF

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AM01471v1

VD O

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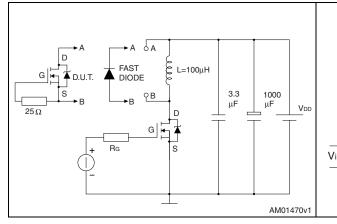
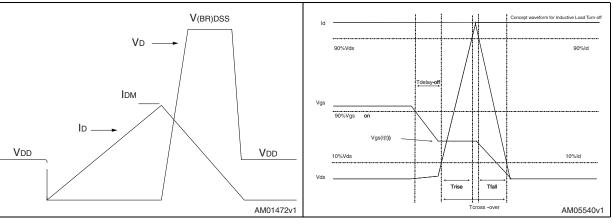




Figure 20. Switching time waveform





4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

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Table 6. Fowering			
Dim.		mm	
Dini.	Min.	Тур.	Max.
A	0.80	0.90	1.00
A1	0.00	0.02	0.05
b	0.95	1.00	1.05
D		8.00	
E		8.00	
D2	7.05	7.20	7.30
E2	4.15	4.30	4.40
e		2.00	
L	0.40	0.50	0.60
aaa		0.10	
bbb		0.10	
ccc		0.10	

Table 8. PowerFLAT[™] 8x8 HV mechanical data



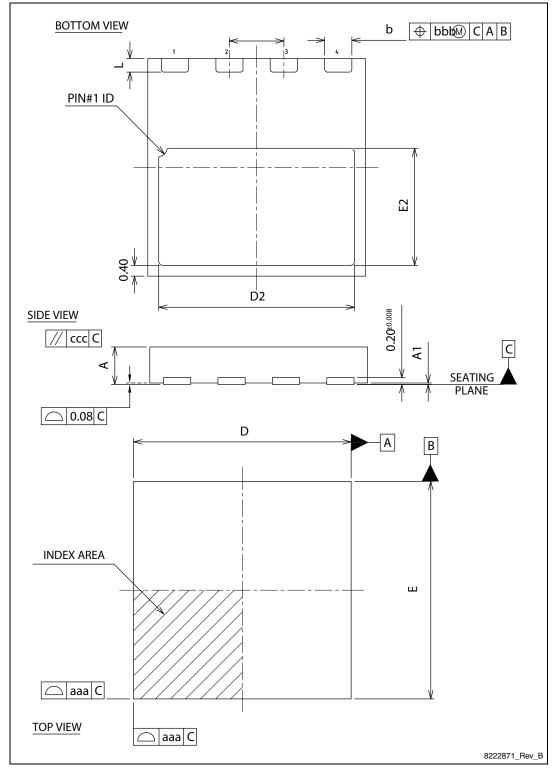


Figure 21. PowerFLAT™ 8x8 HV drawing mechanical data



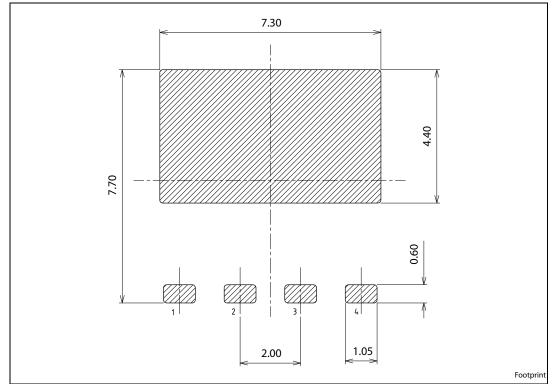


Figure 22. PowerFLAT[™] 8x8 HV recommended footprint



5 Revision history

Date	Revision	Changes
30-Apr-2010	1	First release
08-Jun-2010	2	V _{GS} value has been changed in <i>Table 4</i>
10-Feb-2011	3	Modified R _{DS(on)} value
28-Jul-2011	4	Document status promoted from preliminary data to datasheet Added <i>Section 2.1: Electrical characteristics (curves)</i> Minor text changes
03-Nov-2011	5	Section 4: Package mechanical data has been modified.



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